

From: <William.P.Segall@jci.com>

Importance: Normal

Subject: Diode shorting testing

To: GJD@MIT.EDU

Cc: Thomas.J.Dougherty@jci.com

Date: Mon, 17 Apr 2000 15:16:20 -0500

X-Mimetrack: Serialize by Router on jwimkrs1.na.jci.com/NA/Johnson_Controls(Release 5.0.2 (Intl)|4 November 1999) at 04/17/2000 03:25:31 PM

Gary,

Tom dougherty asked me to forward the results of the latest diode / fuse shorting test. This most recent testing was done using STMicro MOSFETS arranged in a forward biased parallel configuration as shown on the attached schematic. Pictures of the MOSFET test assembly / fixture are also attached. The MOSFET arrangement did not pass it's test, with all four paralleled MOSFETS failing in the open state. The four MOSFETS cases cracked and open circuited upon application of current and subsequent failure, the fuse remained intact.

Please see the attached documents for more information

(See attached file: Mosfet4.jpg)(See attached file: Mosfet2.jpg)(See attached file: Mosfet3.jpg)(See attached file: Mosfet1.jpg)(See attached file: schematic.bmp)

Tom thought that you may want place the pictures and schematic on the WEB site.

If you have any questions or comments please call me.

Thank You,

Bill Segall (414)-228-2485



[Mosfet4.jpg](#)



[Mosfet2.jpg](#)



[Mosfet3.jpg](#)



[Mosfet1.jpg](#)



[schematic.bmp](#)